

**Search Notes**

Application/Control No.

10/694,825

Examiner

Sun J. Lin

Applicant(s)/Patent under  
Reexamination

IKEDA ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	9	3/24/2006	JSL
716	8	3/24/2006	JSL
716	1	3/24/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	9	3/24/2006	JSL
716	8	3/24/2006	JSL
716	1	3/24/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/24/2006	JSL